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Im	JP	2001-156188	A	2001-06-08	JAPAN	$\frac{1}{1}$		ABS	
M	JP	2001-230332	A	2001-08-24	JAPAN	1		ABS	
M	JP	9-116119	A	1997-05-02	JAPAN			ABS	
CMI	JP	2001-512290	A	2001-08-21	JAPAN				X
Jewi .	WO	99/07000	A2	1999-02-02	WO			ABS	7
DWI	JP	9-97849	Α	1997-04-08	JAPAN			ABS	
IND	WO	03/075359	A1	2003-09-12	WO			ABS	
emi	WO	03/075358	A1	2003-09-12	WO			ABS	*
IND	WO	03/103058	A1	2003-12-11	WO			ABS	
IMS	JP	5-304277	A	1993-11-16	JAPAN			ABS	
In	JP	5-81702	B2	1993-11-15	JAPAN		,		X
OTHER DOCUMENTS (Include Name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, seriel, symposium, catalog, etc.) date, pege(s), volume-issue number(s), publisher, city and/or country where published.									
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